

# **Understand Power MOSFET**

## **Data Sheet**

- **Contents**
  - **The Title Page**
  - **Maximum Ratings**
  - **Thermal Data & Thermal Resistance**
  - **Power Dissipation and Current Rating**
  - **Eas Rating & Safe Operation Area (SOA)**
  - **Off-State Characteristics**
  - **On-State Characteristics**
  - **Dynamic Characteristics**
  - **Resistive Switching Characteristics**
  - **Body Diode Characteristics**

- Device type
- Features
- Vdss
- Rdson (max.)
- Id
- Package type
- Maximum ratings
- Thermal data
- Revision data



**N-Channel MOSFET**

**Applications:**

- CRT, TV/Monitor
- Other Applications

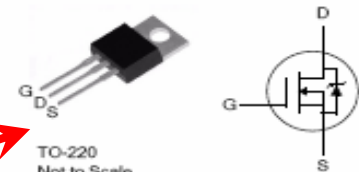
**Features:**

- Lead Free
- Low ON Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves
- Improved UIS Ruggedness

**Ordering Information**

PART NUMBER	PACKAGE	BRAND
FTP18N20	TO-220	FTP/IR20

V <sub>DSS</sub>	R <sub>DS(ON)</sub> (Max.)	I <sub>D</sub>
200V	0.18 Ω	18A



**Absolute Maximum Ratings** T<sub>C</sub>=25°C unless otherwise specified

Symbol	Parameter	Maximum	Units
V <sub>DSS</sub>	Drain-to-Source Voltage (NOTE *1)	200	V
I <sub>D</sub>	Continuous Drain Current	18	A
I <sub>D@ 100 °C</sub>	Continuous Drain Current	Figure 3	
I <sub>DM</sub>	Pulsed Drain Current, V <sub>GS</sub> @ 10V (NOTE *2)	Figure 6	
P <sub>D</sub>	Power Dissipation	156	W
	Derating Factor above 25 °C	1.25	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy L=500 μH, I <sub>D</sub> =28.3 Amps	200	mJ
I <sub>AS</sub>	Pulsed Avalanche Rating	Figure 8	
di/dt	Peak Diode Recovery di/dt (NOTE *3)	3.0	V/ns
T <sub>L</sub>	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds Package Body for 10 seconds	300	°C
T <sub>PKG</sub>		260	
T <sub>J</sub> and T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to 150	

*Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.*

**Thermal Resistance**

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R <sub>θJC</sub>	Junction-to-Case	--	--	0.8	°C/W	Water cooled heatsink, P <sub>D</sub> adjusted for a peak junction temperature of +150 °C.
R <sub>θJA</sub>	Junction-to-Ambient	--	--	62		1 cubic foot chamber, free air.



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# Maximum Ratings

Absolute Maximum Ratings

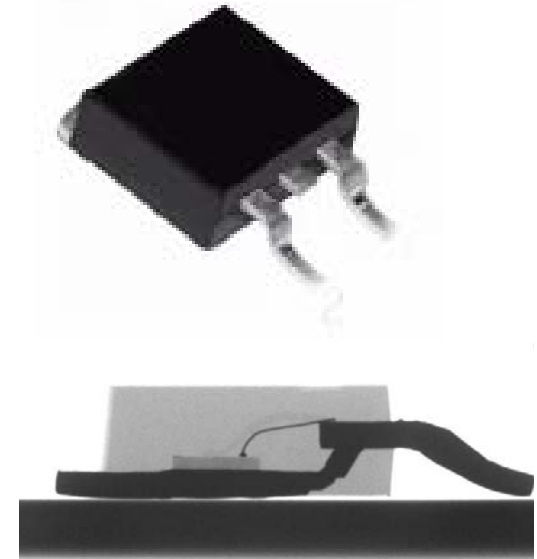
$T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Maximum	Units
$V_{DSS}$	Drain-to-Source Voltage (NOTE *1)	200	V
$I_D$	Continuous Drain Current	18	A
$I_{D@ 100^\circ\text{C}}$	Continuous Drain Current	Figure 3	
$I_{DM}$	Pulsed Drain Current, $V_{GS}@ 10\text{V}$ (NOTE *2)	Figure 6	
$P_D$	Power Dissipation	156	W
	Derating Factor above $25^\circ\text{C}$	1.25	W/ $^\circ\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy L=500 $\mu\text{H}$ , $I_D=28.3$ Amps	200	mJ
$I_{AS}$	Pulsed Avalanche Rating	Figure 8	
dv/dt	Peak Diode Recovery dv/dt (NOTE *3)	3.0	V/ns
$T_L$ $T_{PKG}$	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds	300	$^\circ\text{C}$
	Package Body for 10 seconds	260	
$T_J$ and $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to 150	

**Caution:** Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

- **Thermal Resistances**

- $R_{thjc}$ : Proportional to  $R_{dson}$ , or inverse proportional to die size and current rating
- $R_{thja}$ : Function of packaging type, molding compound, thickness of the lead frame, ...

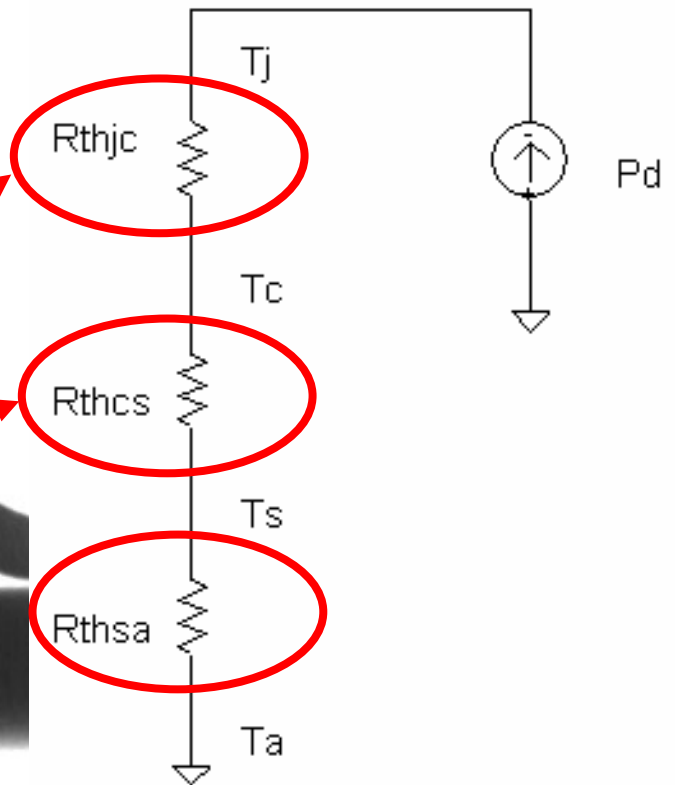
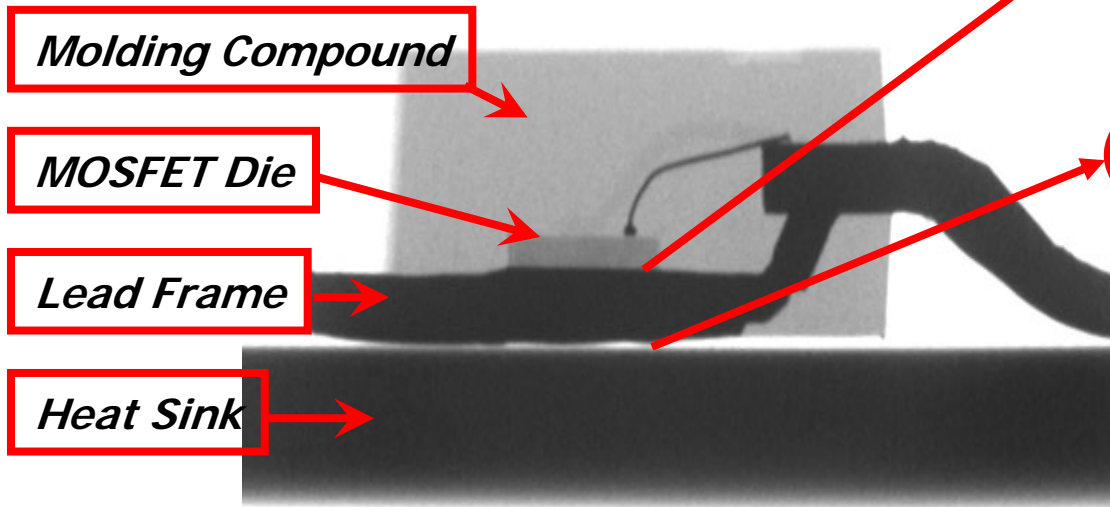


## Thermal Resistance

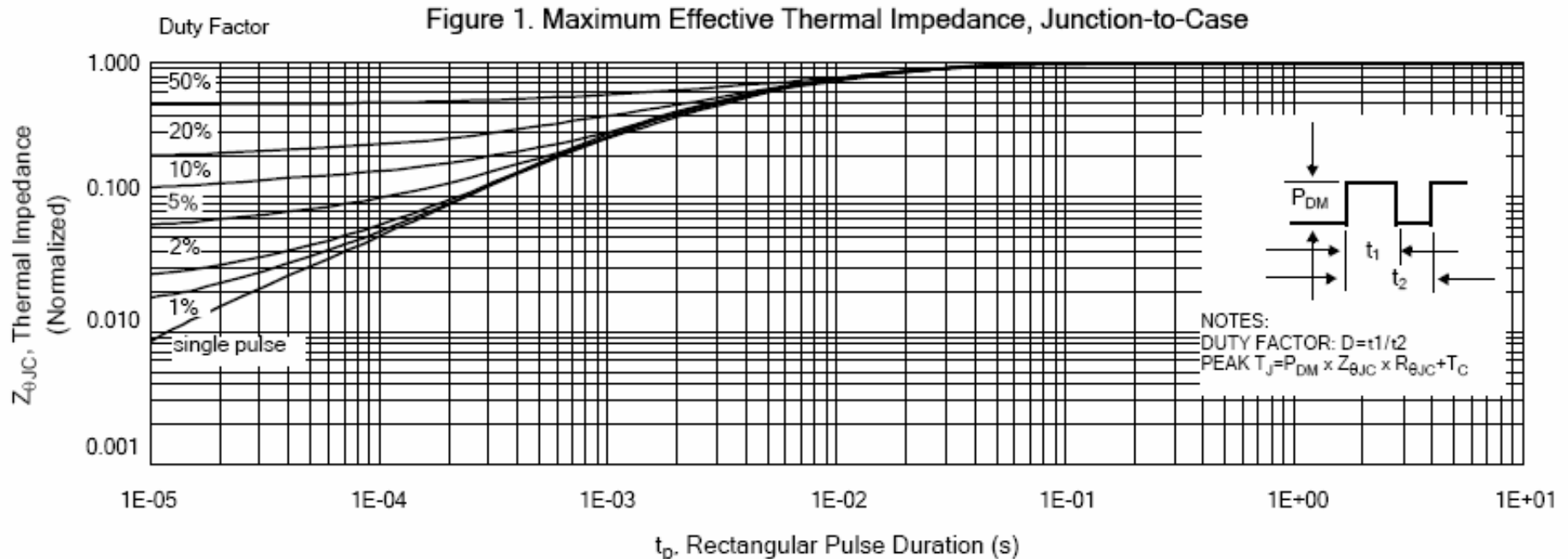
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	--	--	0.8	$^{\circ}C/W$	Water cooled heatsink, $P_D$ adjusted for a peak junction temperature of $+150^{\circ}C$ .
$R_{\theta JA}$	Junction-to-Ambient	--	--	62		1 cubic foot chamber, free air.

- **Equivalent Circuit**

- $R_{thjc}$ : Die-to-case
- $R_{thcs}$ : Case-to- heatsink
- $R_{thsa}$ : Heatsink-to-ambient



- **Maximum Transient Rthjc**
  - Function of duty cycle and period
  - Normalized value on data sheet



- **Calculating Pd**

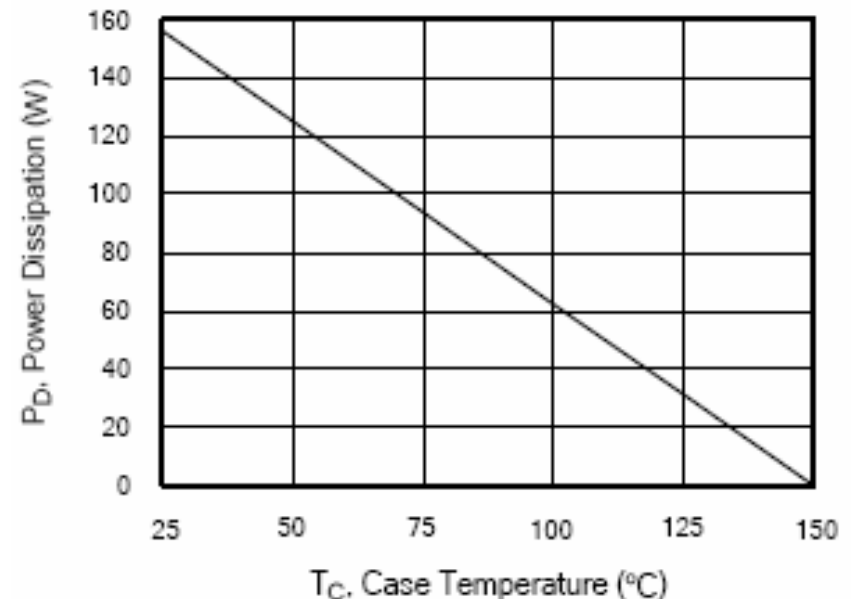
$$T_j = P_d \times R_{thjc} + T_c$$

$$\begin{aligned} P_{d_{\max}} &= (T_{j_{\max}} - T_c) / R_{thjc} \\ &= (150^\circ\text{C} - 25^\circ\text{C}) / (0.8^\circ\text{C}/\text{W}) \\ &= 156\text{W} \end{aligned}$$

- **De-rating Factor**

➤  $1/R_{thjc} = 0.8 \text{ W}/^\circ\text{C}$

Figure 2. Maximum Power Dissipation vs Case Temperature





# Maximum Current Rating Id

## • Calculating Id

$$Pd_{\max} = Id_{\max}^2 \times Rdson$$

$$\begin{aligned} Id_{\max} &= \sqrt{Pd_{\max} / Rdson} \\ &= \sqrt{156W / (0.18\Omega \times 2.6)} \\ &= 18.25 A \end{aligned}$$

$$\begin{aligned} Id_{100^\circ C} &= \sqrt{Pd_{100^\circ C} / Rdson} \\ &= \sqrt{\{(Tj - Tc) / Rthjc\} / Rdson} \\ &= \sqrt{\{(150 - 100) / 0.8\} / (0.18 \Omega \times 2.6)} \\ &= 11.55 A \end{aligned}$$

Figure 3. Maximum Continuous Drain Current vs Case Temperature

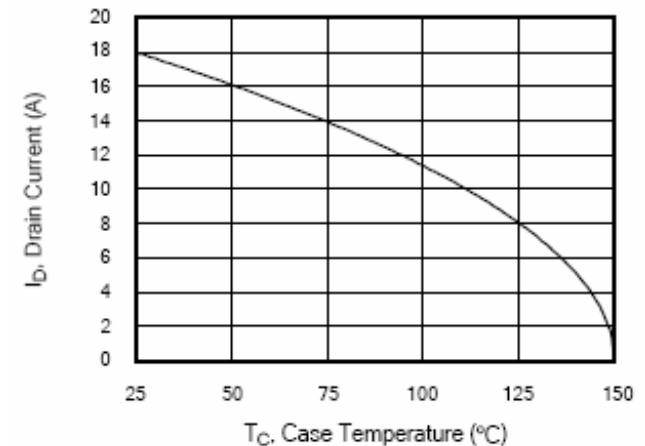
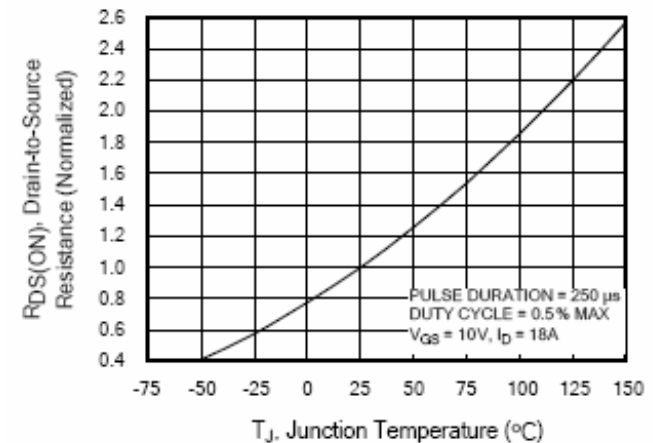


Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature

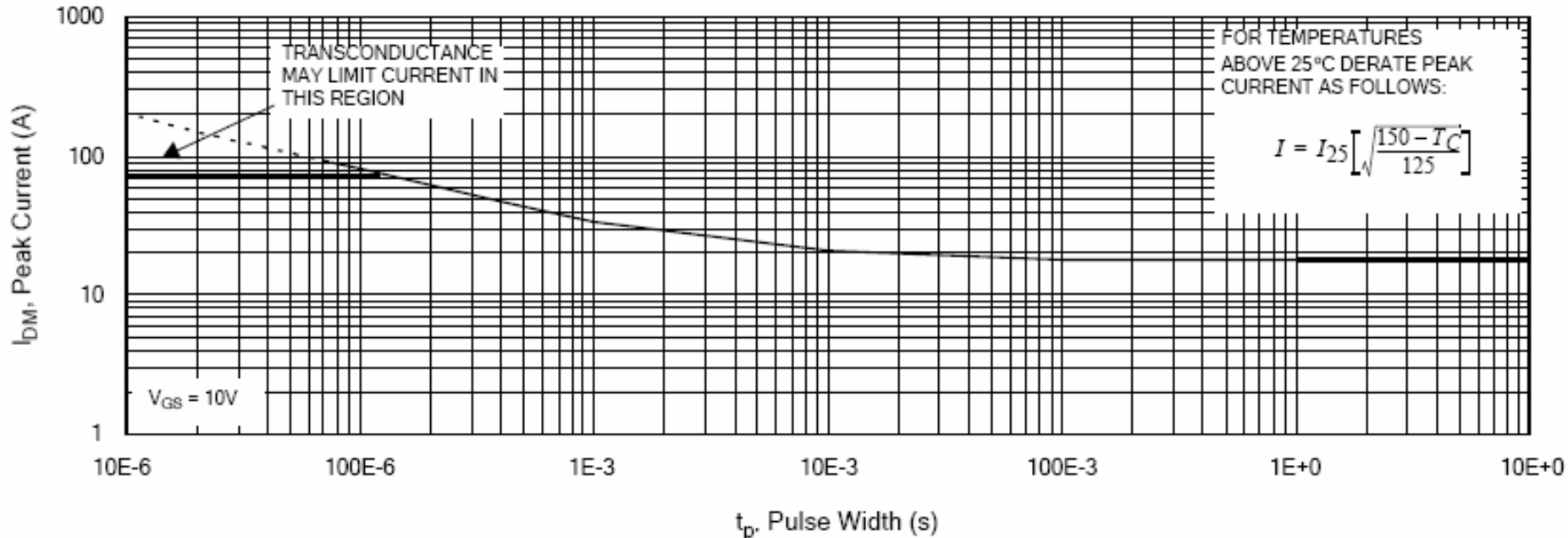


# Maximum Pulsed Current

- **Maximum Pulsed Id**

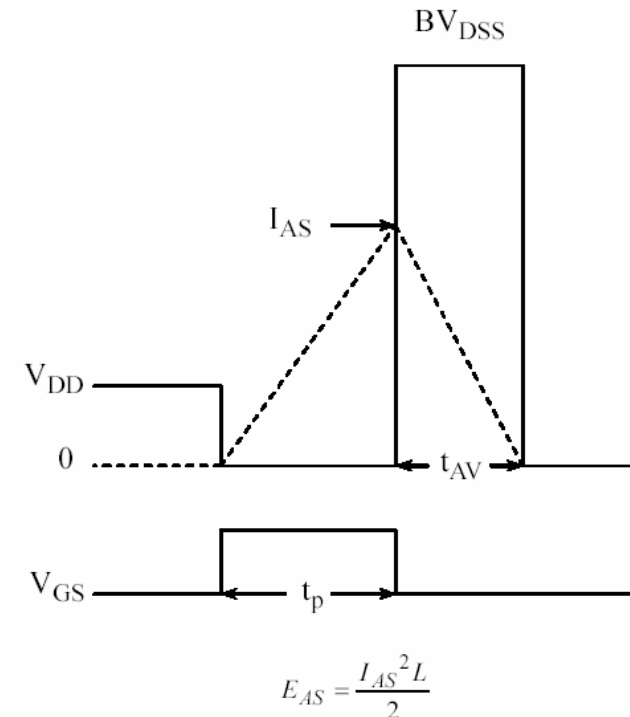
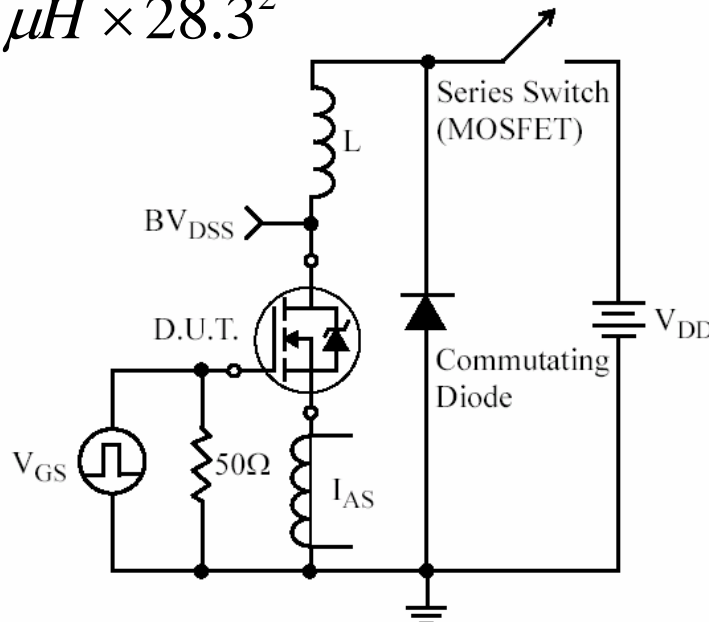
- Function of transient  $R_{thjc}$ , duty cycle, and period
- Limited by Gfs or Vgs capability

Figure 6. Maximum Peak Current Capability



- **Eas Rating**

$$\begin{aligned}
 E_{as} &= \frac{1}{2} \times L \times I_{as}^2 \\
 &= \frac{1}{2} \times 500 \mu H \times 28.3^2 \\
 &= 200 \text{ mJ}
 \end{aligned}$$

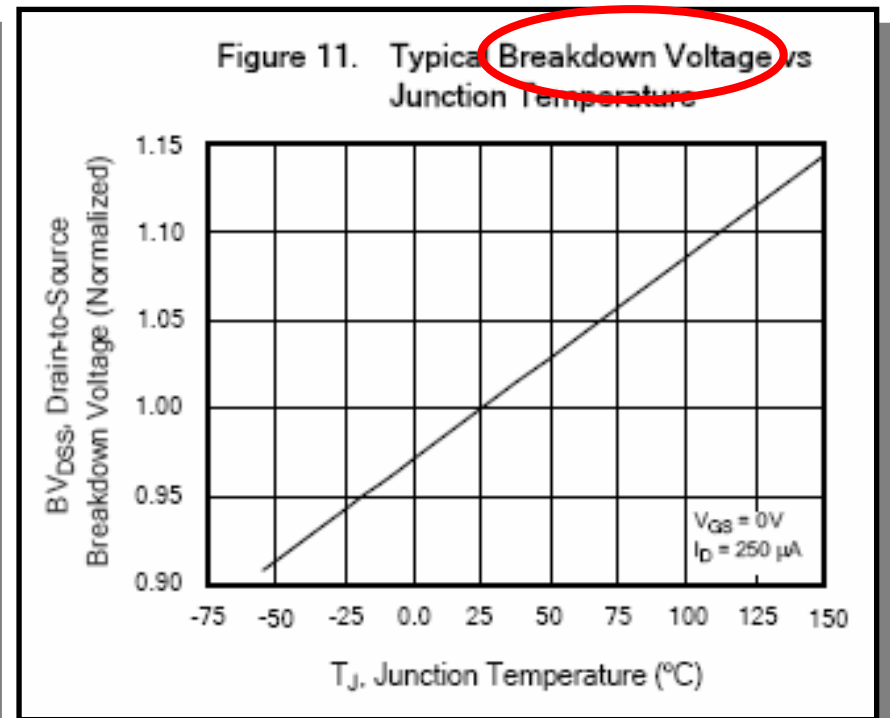
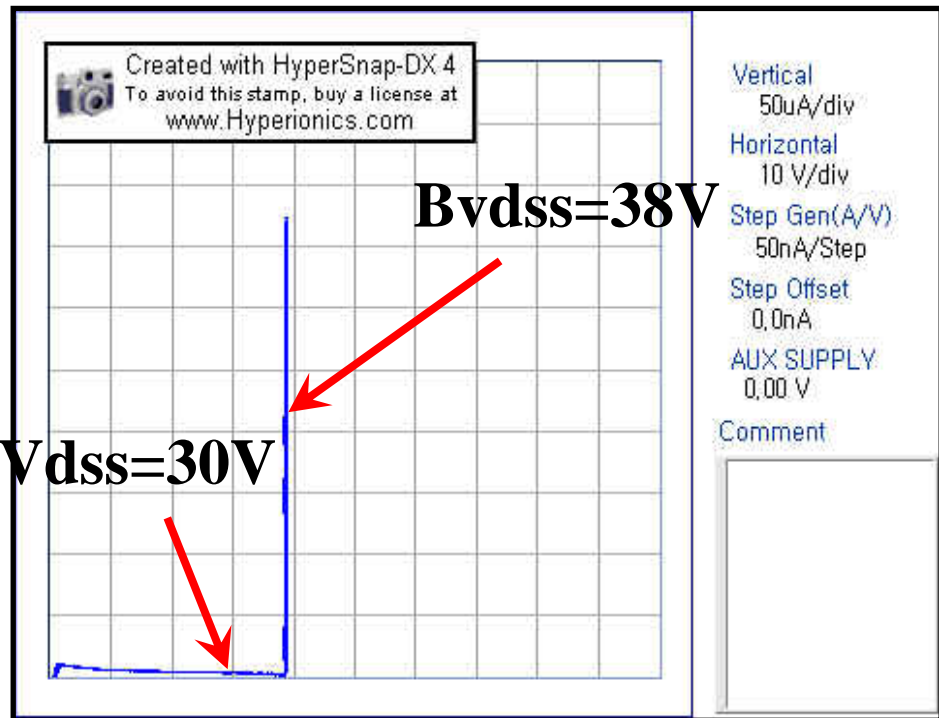


- **MOSFET at Off-State**
  - $BV_{DSS}$ : Breakdown voltage
  - $I_{DSS}$ : Drain leakage current
  - $I_{GSS}$ : Gate leakage current

OFF Characteristics  $T_J=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	200	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient, Figure 11.	--	0.25	--	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D=250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	25	$\mu A$	$V_{DS}=200V, V_{GS}=0V$
		--	--	250		$V_{DS}=160V, V_{GS}=0V$ $T_J=125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+30V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V$

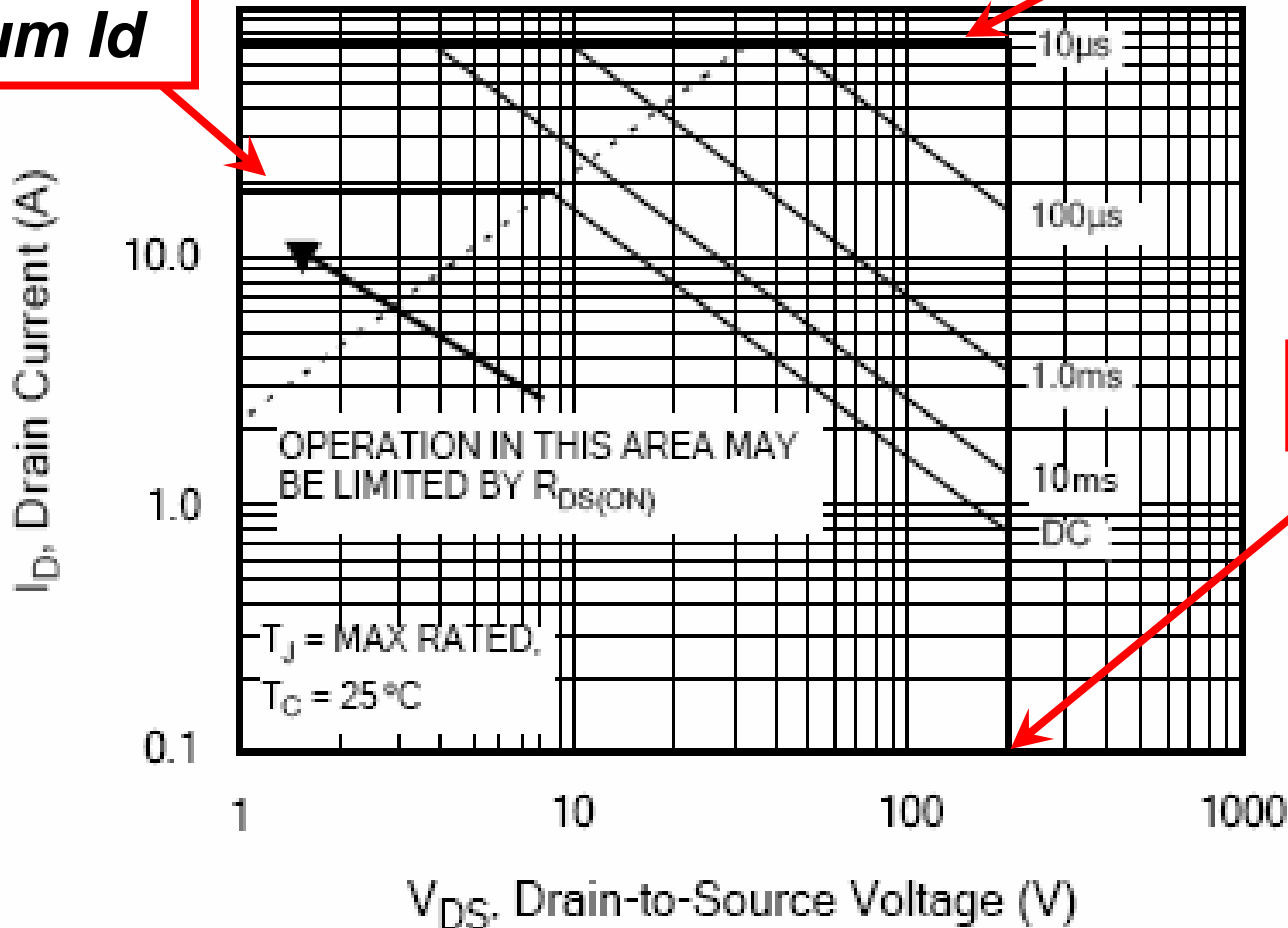
- **Minimum Bvdss & Maximum Vdss**
  - Bvdss: Minimum breakdown voltage
  - Vdss: Maximum rated drain voltage



# Safe Operation Area (SOA)

- MOSFET SOA Curve

**Maximum Id**



**Maximum Pulsed Id**

**Vdss**

- **MOSFET at On-State**

- $R_{DS(on)}$ : On-state resistance

- Function of  $V_{GS}$  and  $I_D$

- **Watch for the test condition!**

- $V_{th}$ : Threshold voltage

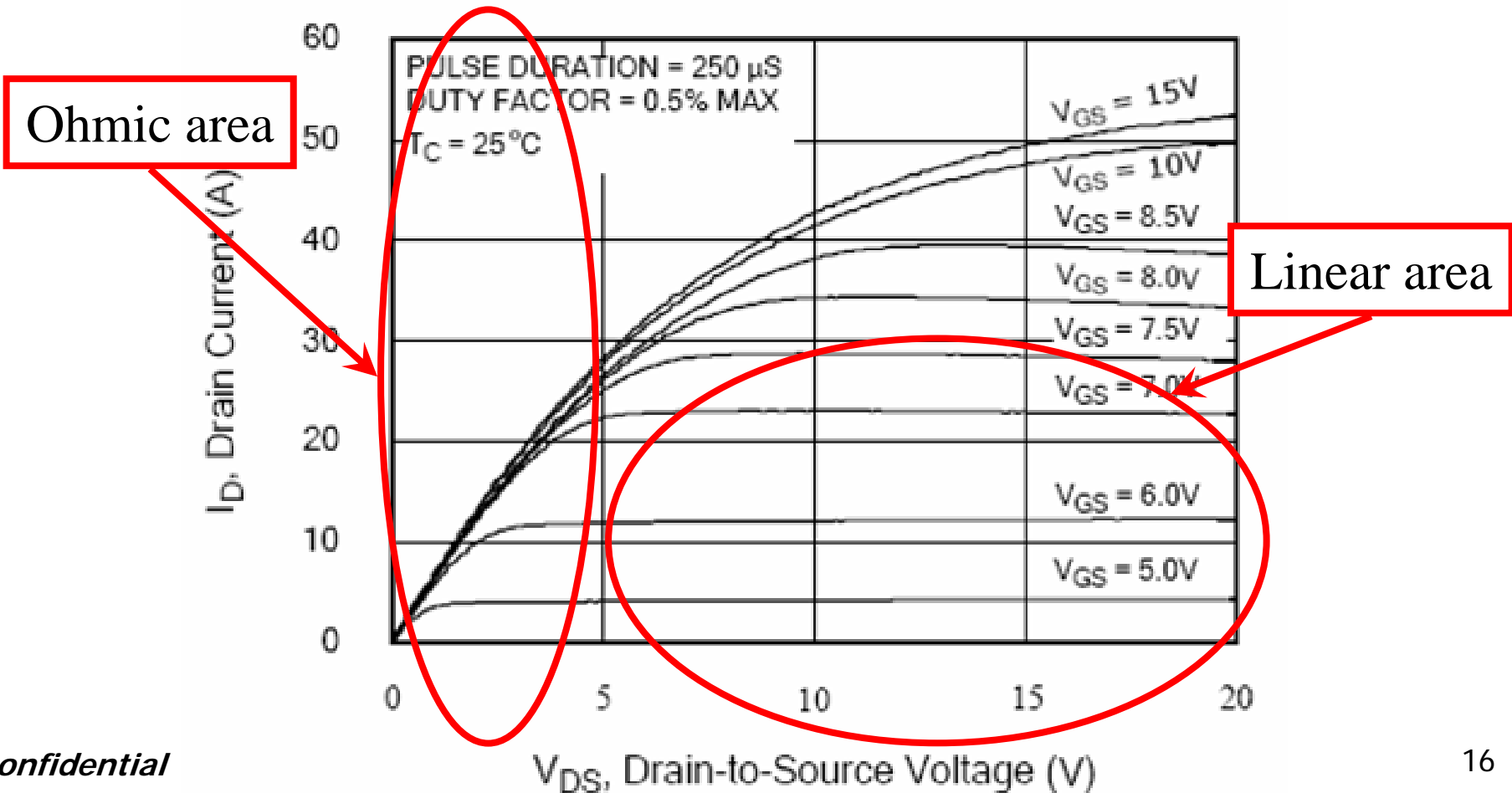
- $g_{fs}$ : Trans-conductance,  $g_{fs} = \Delta I_D / \Delta V_{GS}$

ON Characteristics  $T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance Figure 9 and 10.	--	0.14	0.18	$\Omega$	$V_{GS}=10\text{V}, I_D=10.8\text{A}$ (NOTE *4)
$V_{GS(TH)}$	Gate Threshold Voltage, Figure 12.	2.0	--	4.0	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
$g_{fs}$	Forward Transconductance	--	14.4	--	S	$V_{DS}=15\text{V}, I_D=18\text{A}$ (NOTE *4)

# Rdson Characteristic

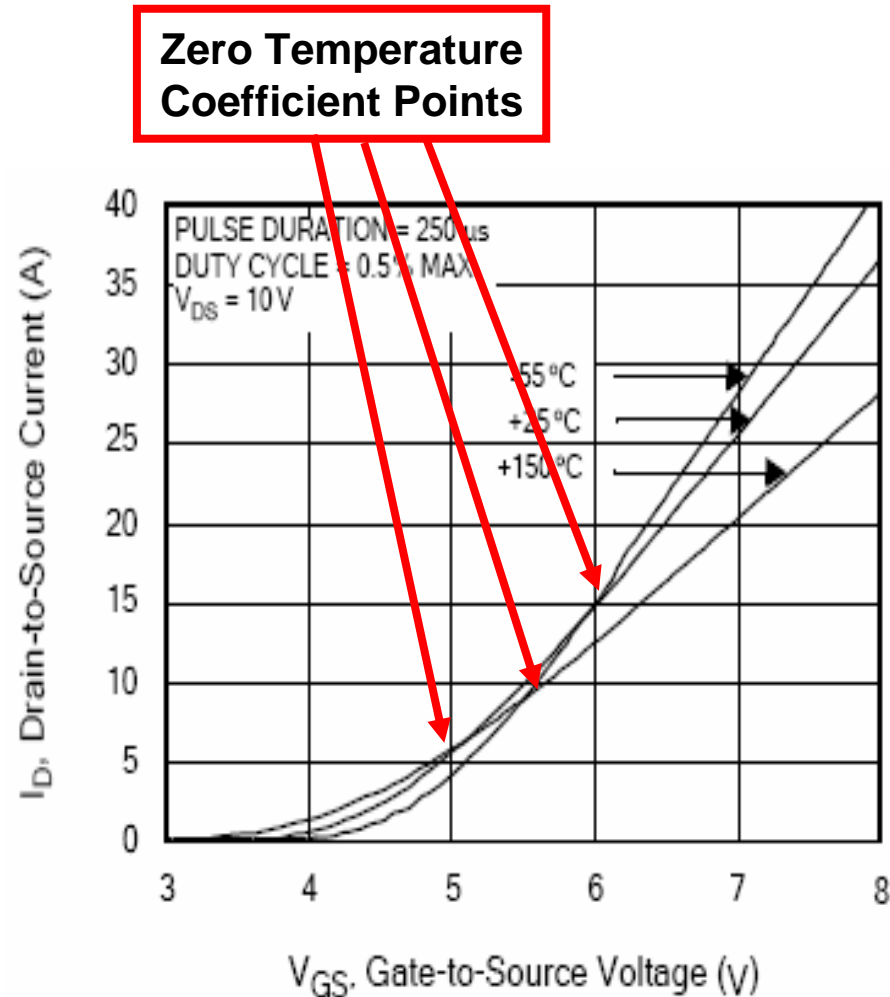
- $R_{dson} = \Delta V_{ds} / \Delta I_d$





- **Zero Temperature Coefficient**

- Important for paralleling MOSFETs
- MOSFET is supposed to operate above the zero temperature coefficient
- MOSFETs might be thermally running away if operates below this zero temperature coefficient point



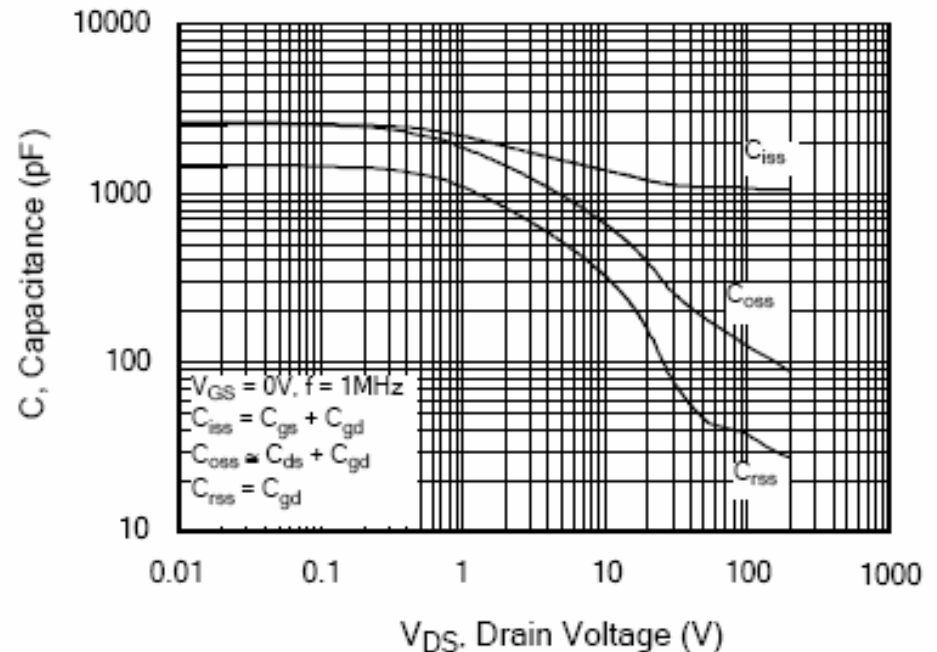
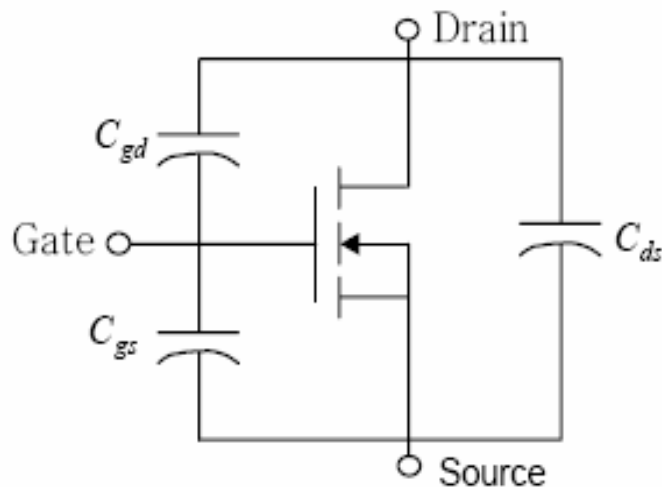
- **MOSFET at Dynamic (Switching) State**
  - $C_{iss}$ ,  $C_{oss}$ , and  $C_{rss}$
  - $Q_g$ ,  $Q_{gd}$ , and  $Q_{gs}$
  - Guaranteed by design

Dynamic Characteristics    Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$C_{iss}$	Input Capacitance	--	1145	--	pF	$V_{GS}=0V$ $V_{DS}=25V$ $f=1.0MHz$ Figure 14
$C_{oss}$	Output Capacitance	--	105	--		
$C_{rss}$	Reverse Transfer Capacitance	--	310	--		
$Q_g$	Total Gate Charge	--	40	--	nC	$V_{DS}=100V$ $I_D=18A$ $V_{GS}=10V$ Figure 15
$Q_{gs}$	Gate-to-Source Charge	--	10.2	--		
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	--	20.3	--		

- **MOSFET Capacitances**

- Input Capacitance:  $C_{iss} = C_{gd} + C_{gs}$
- Output Capacitance:  $C_{oss} = C_{gd} + C_{ds}$
- Miller Capacitance:  $C_{rss} = C_{gd}$



# Gate Charge and Capacitance

- Physical Connections

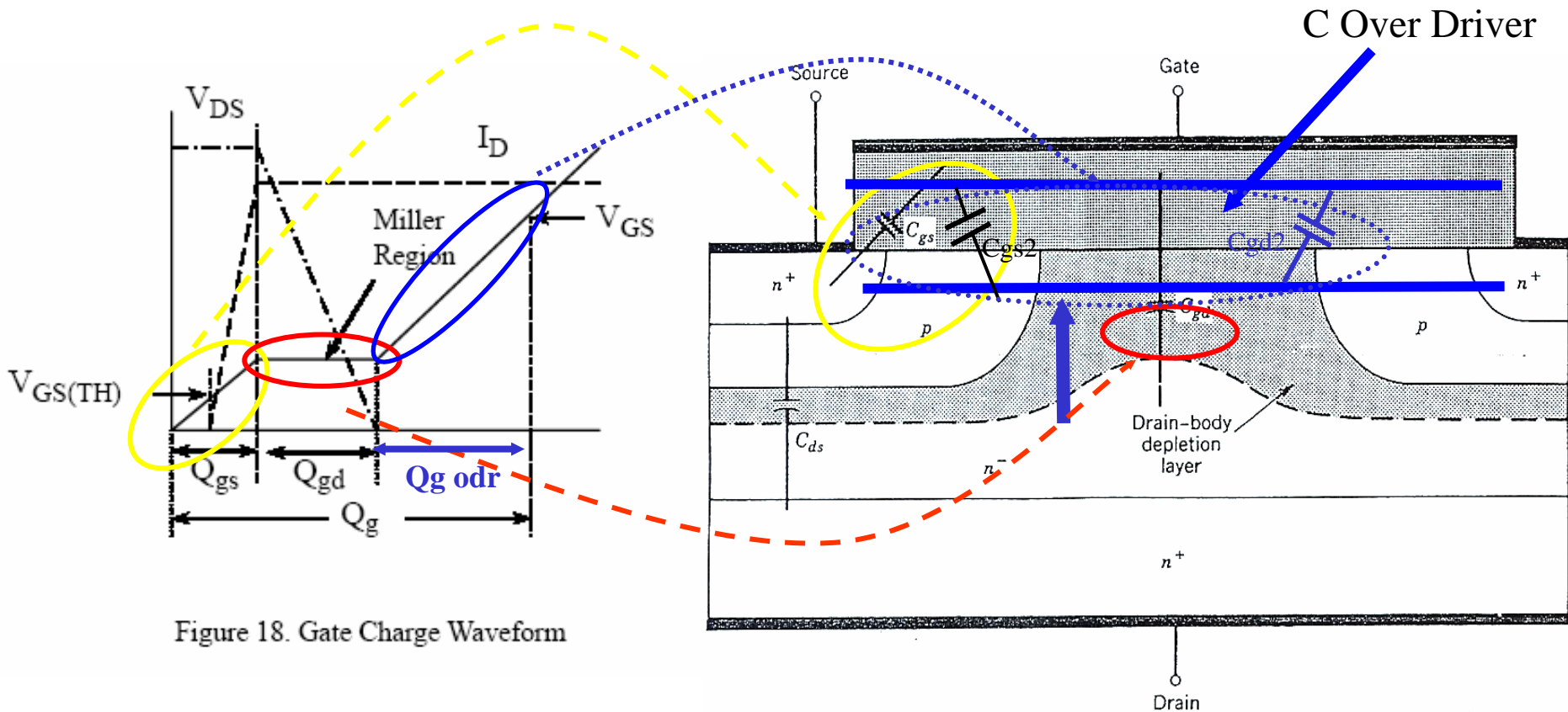
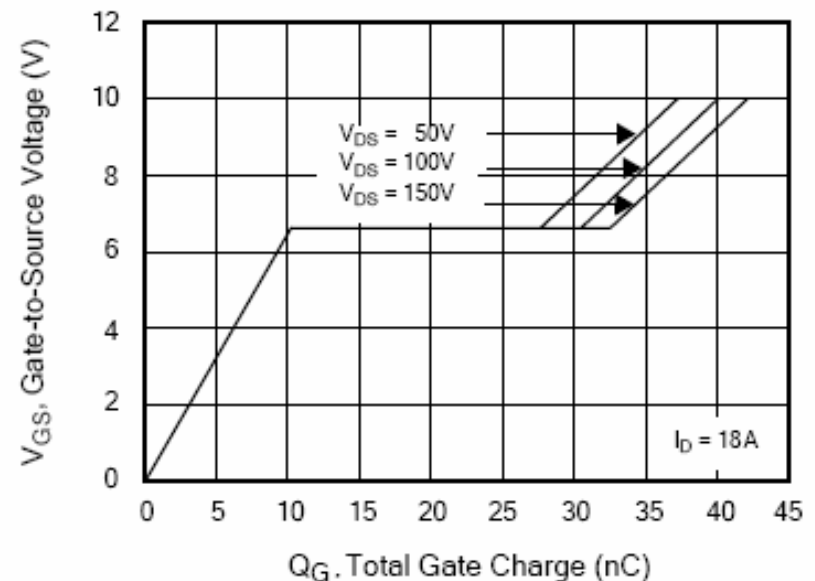
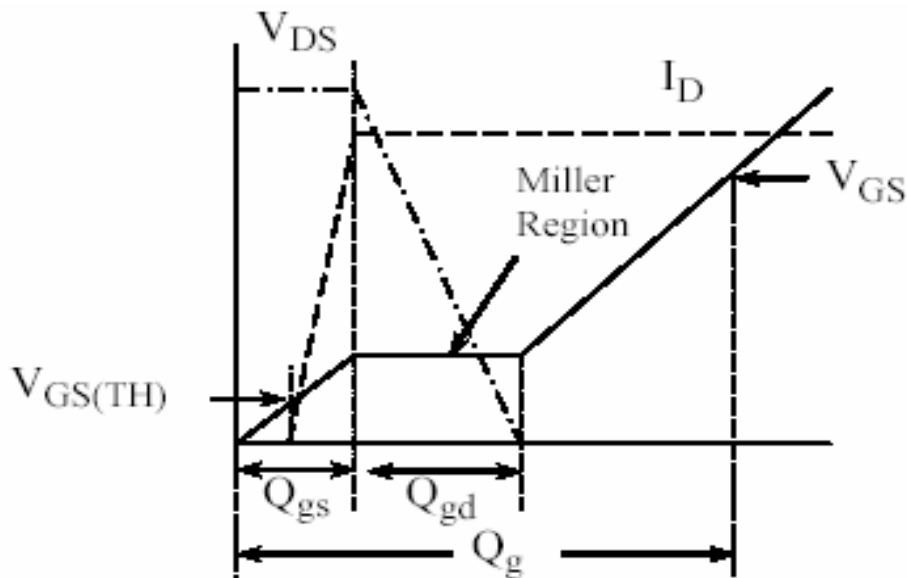


Figure 18. Gate Charge Waveform

- **Smaller is better?**

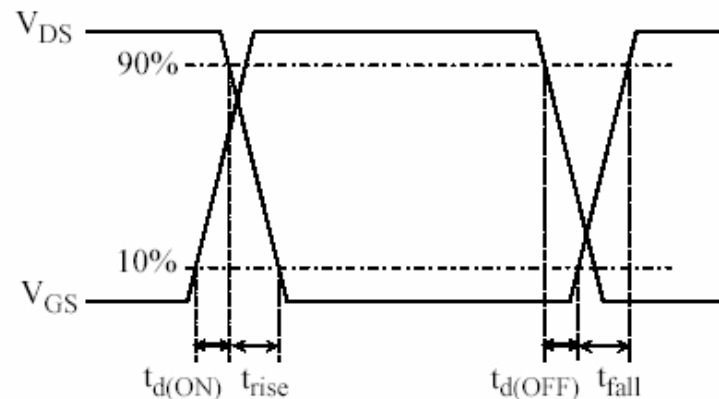
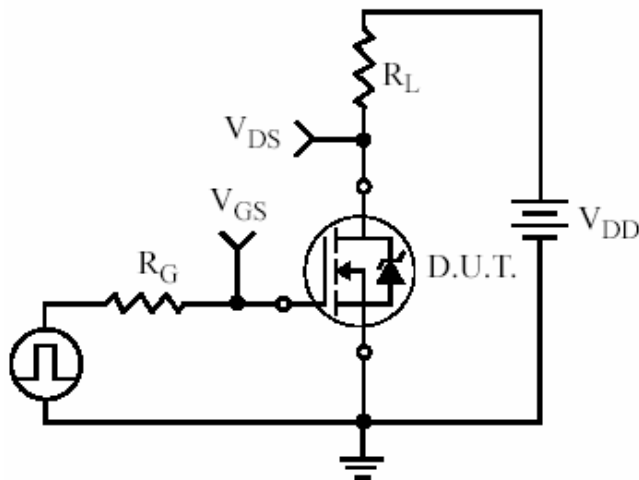
- Smaller  $Q_g$ , less switching time → Less power losses
- Smaller  $Q_{gd}$ , fast  $dv/dt$  → Worse the EMC problem



- Resistive Switching Delays

Resistive Switching Characteristics      Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$t_{d(ON)}$	Turn-on Delay Time	--	18	--	ns	$V_{DD}=100V$ $I_D=18A$ $V_{GS}=10V$ $R_G=2.4\Omega$
$t_{rise}$	Rise Time	--	40	--		
$t_{d(OFF)}$	Turn-Off Delay Time	--	40	--		
$t_{fall}$	Fall Time	--	20	--		



- **MOSFET Body Diode Operation**
  - $V_{SD}$ : Forward drop voltage
  - $t_{rr}$ : Reverse recovery time
  - $Q_{rr}$ : Reverse recovery charges

**Source-Drain Diode Characteristics**  $T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$I_S$	Continuous Source Current (Body Diode)	--	--	18	A	Integral pn-diode in MOSFET
$I_{SM}$	Maximum Pulsed Current (Body Diode)	--	--	72	A	
$V_{SD}$	Diode Forward Voltage	--	--	1.5	V	$I_S=18\text{A}$ , $V_{GS}=0\text{V}$
$t_{rr}$	Reverse Recovery Time	--	225	337	ns	$V_{GS}=0\text{V}$
$Q_{rr}$	Reverse Recovery Charge	--	1300	1950	nC	$I_F=18\text{A}$ , $di/dt=100\text{A}/\mu\text{s}$

# Body Diode Characteristics

- It is a Parasitic Diode
- **Watch for  $dv/dt$  Failure!**
  - Resonant mode
  - Dead time operation

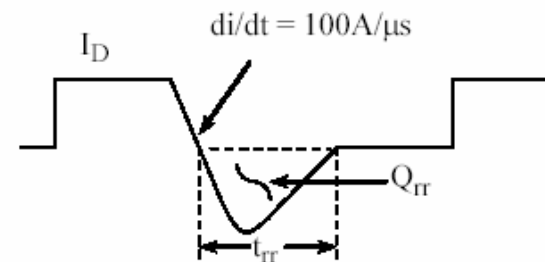
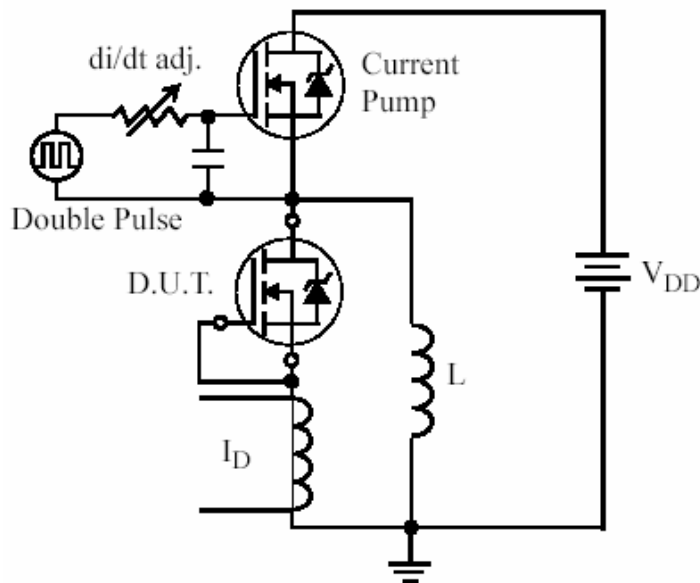
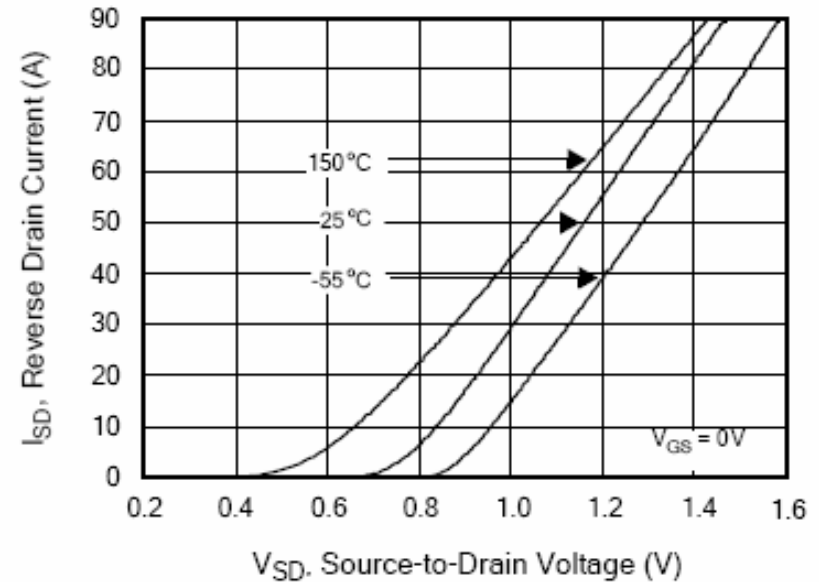


Figure 22. Diode Reverse Recovery Waveform



**End of Presentation**

**Thank You!**